

L Number	Hits	Search Text	DB	Time stamp
1	464	(detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:19
2	396	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:11
3	326	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:12
4	32	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4) and (second near4 scal\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:21
5	11	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4) and (second near4 scal\$4) and (locat\$4 with defect\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:16
6	4	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4) and (second near4 scal\$4) and (locat\$4 with defect\$4) and (magnif\$6 near4 imag\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:17
7	9	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4) and (second near4 scal\$4) and (scal\$4 near factor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:20
8	5	((detect\$5 near4 defect\$5) and imag\$4 and(scal\$4 near4 (factor or value))) and control\$4) and stor\$4 and compar\$4) and (second near4 scal\$4) and (scal\$4 near factor) and (second near2 scal\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:22
9	241	(observ\$4 near4 (sample or specimen or defect)) and (imag\$4 near2 pickup)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:23
10	9	((observ\$4 near4 (sample or specimen or defect)) and (imag\$4 near2 pickup)) and (stor\$4 near4 (information or data or location or position) with area)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:33
11	138	(scale adj factor) and (detect\$5 with defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:41
12	3	((scale adj factor) and (detect\$5 with defect)) and ((mov\$4 or position\$4) with (sample or wafer or specimen or substrate) with defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:36
13	43	((scale adj factor) and (detect\$5 with defect)) and (inspect\$5 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/08/13 18:43

14	13	((scale adj factor) and (detect\$5 with defect)) and (inspect\$5 near4 defect)) and ((position\$3 or mov\$4) with (sample or specimen or wafer or substrate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:45
15	11	((scale adj factor) and (detect\$5 with defect)) and (inspect\$5 near4 defect)) and ((position\$3 or mov\$4) with (sample or specimen or wafer or substrate))) and imag\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:45
16	3	((scale adj factor) and (detect\$5 with defect)) and (inspect\$5 near4 defect)) and ((position\$3 or mov\$4) with (sample or specimen or wafer or substrate))) and imag\$5) and (locat\$5 with defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:47
17	1	((scale adj factor) and (detect\$5 with defect)) and (inspect\$5 near4 defect)) and ((position\$3 or mov\$4) with (sample or specimen or wafer or substrate))) and imag\$5) and (locat\$5 with defect)) and display\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:52
18	1180	(defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:59
19	764	((defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))) and display\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:55
20	281	((defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))) and display\$4) and (locat\$5 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:56
21	191	((defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))) and display\$4) and (locat\$5 near4 defect)) and (compar\$5 near4 imag\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:57
22	1	((defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))) and display\$4) and (locat\$5 near4 defect)) and (compar\$5 near4 imag\$4)) and (second near scale)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 18:57
23	1	((defect near4 inspect\$5) and stor\$4 and (imag\$4 with (sample or wafer or substrate))) and ((first and second) near scale)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/13 19:00